

Title (en)

METHOD FOR DETERMINING A HIGH-REFLECTION CUT OF A GEM, METHOD FOR CUTTING A HIGH-REFLECTION GEM, AND THE CUT HIGH-REFLECTION GEM

Title (de)

VERFAHREN ZUR FESTLEGUNG EINES EDELSTEINSCHLIFFS MIT HOHER REFLEKTION, VERFAHREN ZUM SCHLEIFEN EINES EDELSTEINS MIT HOHER REFLEKTION SOWIE GESCHLIFFENER EDELSTEIN MIT HOHER REFLEKTION

Title (fr)

PROCEDE PERMETTANT DE DETERMINER LA TAILLE HAUTE REFLEXION D'UNE PIERRE PRECIEUSE, PROCEDE DE TAILLE HAUTE REFLEXION D'UNE PIERRE PRECIEUSE ET PIERRE PRECIEUSE TAILLEE A HAUTE REFLEXION

Publication

EP 1001690 A1 20000524 (DE)

Application

EP 98938714 A 19980730

Priority

- DE 19734036 A 19970806
- EP 9804772 W 19980730

Abstract (en)

[origin: US6474102B1] The invention relates to a method for determining a high-reflection cut of a gem, a method for cutting a high-reflection gem, and a cut high-reflection gem. According to the invention, the gems have at least three lower part main facets and at least three upper part main facets, the angle between the lower part main facets and the girdle plane being greater than the angle between the upper part main facets and the girdle plane. A table replaces the upper part main facets at an angle of 0°. The lower part main facet angle is between 41° and 46° and the upper part main facet angle corresponds to an angle from a group of predetermined preferred angles. The group of angles is determined according to the average refraction of light n (between 1.50 and 3.00) of the raw material being cut and the lower part main facet angle.

IPC 1-7

A44C 17/00

IPC 8 full level

A44C 17/00 (2006.01)

CPC (source: EP US)

A44C 17/001 (2013.01 - EP US)

Designated contracting state (EPC)

AT BE CH DE FR GB IT LI LU NL

DOCDB simple family (publication)

US 6474102 B1 20021105; AT E280514 T1 20041115; DE 19734036 A1 19990211; DE 59812178 D1 20041202; EP 1001690 A1 20000524; EP 1001690 B1 20041027; IL 125634 A0 19990411; IL 125634 A 20030917; JP 2001513340 A 20010904; WO 9907244 A1 19990218

DOCDB simple family (application)

US 46341800 A 20000204; AT 98938714 T 19980730; DE 19734036 A 19970806; DE 59812178 T 19980730; EP 9804772 W 19980730; EP 98938714 A 19980730; IL 12563498 A 19980803; JP 2000506848 A 19980730